

Worldwide availability

Our expert teams are available to assist you wherever you are located. We have subsidiaries and distribution partners in key national nations, in order to assist our customers as a reliable production partner.



Standardized industrial metrology systems

Optical and contact measurement systems for the production line, or in the metrology lab



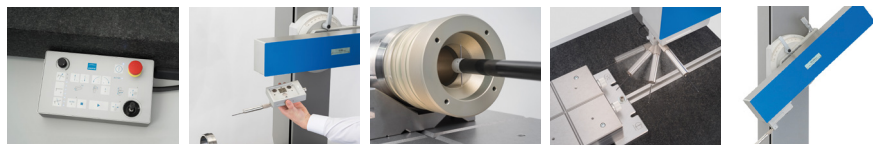
Mobile roughness measurement

Portable roughness systems from the all-in-one W5, to the industry leading wireless W10. These systems are capable of a wide range of skidded measurement tasks, with an extensive array of probes and accessories, delivering shop floor QC lab capability. Simplified data collection using wireless Bluetooth® interface.



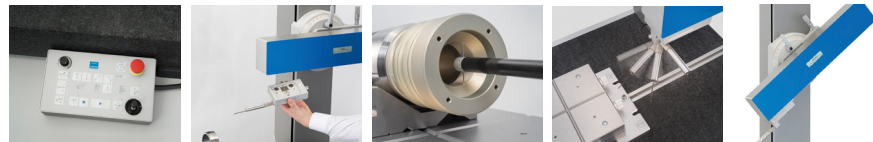
Contour measurement systems

Roughness and contour systems can both be used depending on the measuring task, work piece geometry and access to the measurement location. Improved operational speeds of 20mm/s on both the traverse unit and the measuring column help deliver fast, completely automated, CNC measuring routines.



Contour measurement systems

The W800 series measuring instruments are designed for demanding tasks in functional roughness metrology using a modular design concept. Roughness and contour systems can both be used depending on the measuring task, work piece geometry and access to the measurement location. Improved operational speeds of 20mm/s on both the traverse unit and the measuring column help deliver fast, completely automated, CNC measuring routines.

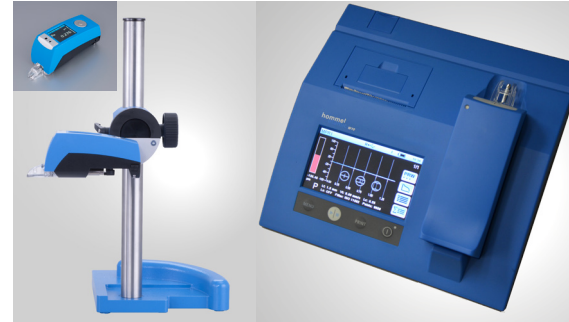


Roughness and contour measurement with maximum precision

The Nanoscan 855 series measuring instrument combines roughness and contour measurements, using a single probe, all in one complete measuring pass. This helps deliver significant accuracy and unparalleled flexibility over a large range of surface metrology measurement tasks, including CNC mode.



WAVELINE W5 WAVELINE W20



WAVELINE 600



WAVELINE W800



WAVELINE Nanoscan 855



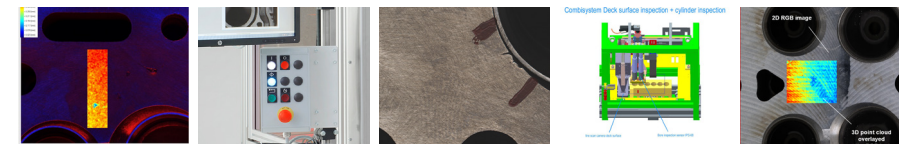
Optical shaft measurement

Opticline C series shaft measuring systems offer maximum gauge repeatability and reproducibility from 0.001mm. With different configurations, such as a high-precision C-axis, or multi-sensor system, the performance capability can be customized to suit your requirements.



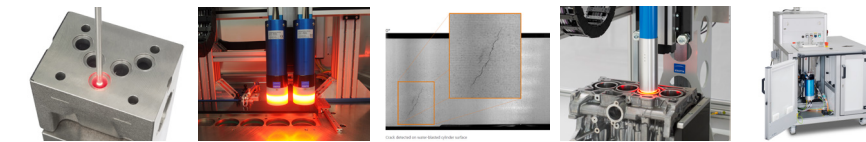
Optical inspection systems for critical plane surfaces

Innovative camera lighting technology with adaptive dynamic masking are used to identify porosities, scratches, non-cleanup conditions, edges, etc., with a high level of reliability. The systems can be used in conjunction with optical bore systems as a



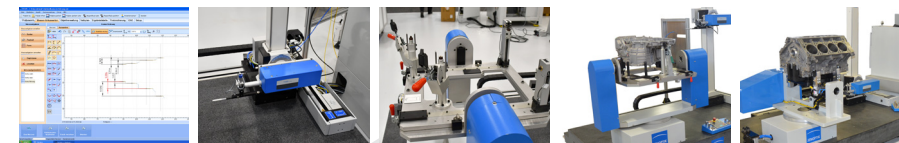
Optical small bore surface defect inspection

Optical bore inspection sensor technology that scans the entire surface of the part while delivering high-resolution, distortion free images of the surface. Common surface defects, such as cavities, porosities, scratches, chips, contaminants, etc., can be reliably detected. Systems are available in offline configurations with manual part load, or inline configurations with automated part load.



Individually customized roughness and contour work station

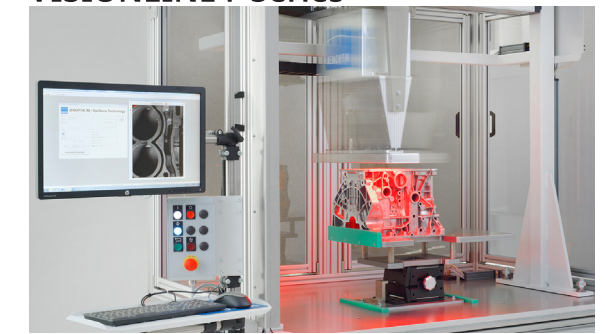
Individually tailored standard solution for specific workpieces based on the T8000 platform. The Jenoptik Wavemove measuring station allows individual, complex, CNC-controlled, fully automated roughness and contour measurements to be performed right on the production line.



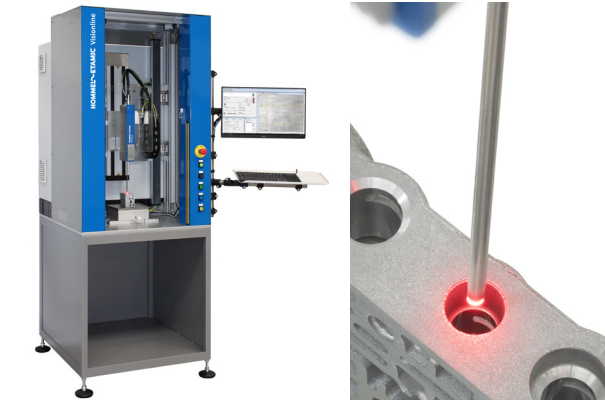
OPTICLINE CS - C1214 Series



VISIONLINE F Series



VISIONLINE V205/V220



WAVEMOVE

